



AF/IFW
PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Boyd et al

Serial No. 10/606,022

Filed: June 24, 2003

For: SYSTEM AND METHOD
FOR INTEGRATING IN-SITU
METROLOGY WITHIN A
WAFER PROCESS

Examiner: PERRIN, J.

Art Unit: 1746

Atty Docket No. LAM2P425

Date: February 6, 2007

CERTIFICATE OF MAILING

I hereby certify that this paper (along with any paper referred to as being attached or enclosed) is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA, 22313-1450 on February 6, 2007.

Signed: _____

George B. Leavell

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

Transmitted herewith is an Amendment in the above-identified application.
The fee has been calculated as shown below.

	Claims Remaining After <u>Amendment</u>	Highest Previously <u>Paid For Extra</u>	Present	SMALL ENTITY <u>RATE FEE</u>	OR	LARGE <u>RATE FEE</u>	ENTITY
TOTAL CLAIMS	<u>17</u> -	<u>21</u>	<u>00</u>	X09 = \$	OR	X18 = \$	
INDEP CLAIMS	<u>03</u> -	<u>03</u>	<u>00</u>	X43 = \$	OR	X86 = \$	
[] Multiple Dependent Claim Present and Fee Not Previously Paid				\$145		X290	\$
TOTAL				\$ _____		\$ _____	



Applicant(s) hereby petition for a _____ month(s) extension of time to respond to the outstanding Office Action.
Applicant(s) believe that no (additional) Extension of Time is required; however, if it is determined that such an extension is required, Applicant(s) hereby petition that such an extension be granted and authorize the Commissioner to charge the required fees for an Extension of Time under 37 CFR 1.136 to Deposit Account No. 50-0805 (Order No. LAM2P425).



Enclosed is our Check No. _____ in the amount of _____ to cover the additional claim fee and/or extension of time fees.



If the required fees are missing or any additional fees are required to facilitate filing the enclosed response, please charge such fees or credit any overpayment to Deposit Account No. 50-0805 (Order No. LAM2P425).
A copy of this sheet is enclosed.

Respectfully submitted,
MARTINE PENILLA & GENCARELLA, LLP

George B. Leavell, Esq.
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Signed: _____

George B. Leavell

AMENDMENT AND RESPONSE TO OFFICE ACTION

Commissioner for Patents
Alexandria, VA 22313-1450

In response to the Office Action mailed December 14, 2006, please amend the above-referenced application as follows:

Amendments to the Specification begin on page 2 of this paper.

A complete listing of claims with their current status begins on page 3 of this paper.

Remarks begin on page 7 of this paper.